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Correction

Heavy Ion Characterization of a Radiation Hardened Flip-Flop Optimized for Subthreshold Operation. *J. Low Power Electron. Appl.* 2012, *2*, 168-179

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We have found the following error in the title of this article which was recently published in *J. Low Power Electron. Appl.* [1]:

The correct title should be: **Heavy Ion Characterization of a Radiation Hardened Flip-Flop Optimized for Subthreshold Operation**.

We apologize for any inconvenience caused to the readers.

References

1. Chavan, A.; Palakurthi, P.; MacDonald, E.; Neff, J.; Bozeman, E. Hardened Flip-Flop Optimized for Subthreshold Operation Heavy Ion Characterization of a Radiation. *J. Low Power Electron. Appl.* **2012**, *2*, 168–179.